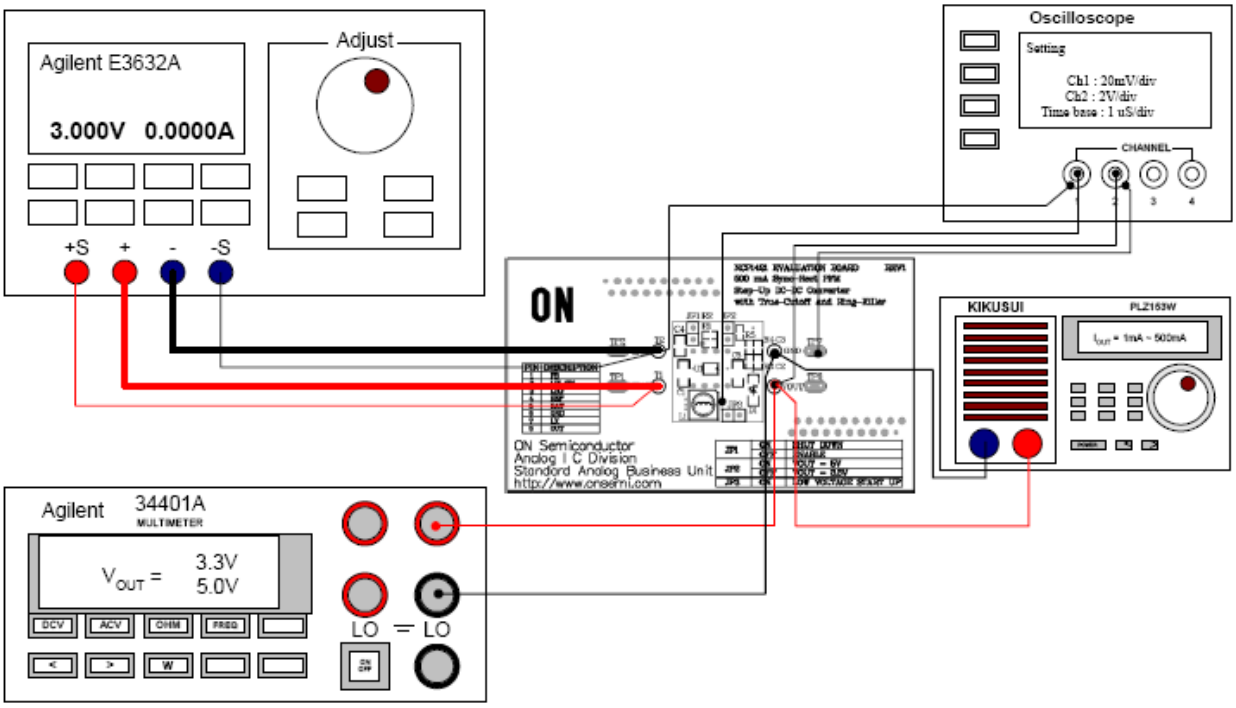
ON Semiconductor

Test Procedure for the NCP1422GEVB Evaluation Board



1. Connect the test setup as shown above.
2. **TURN OFF the JP**; (enable the device).
3. Set the Power Supply to 3.0V and apply to TP1, TP2, (T1, T2).
4. Apply 500mA loading form the electric load.
5. Check the input current (I_{IN}), output voltage (V_{OUT}) and output ripple;
   - For V_{OUT} = 3.3V; **JP2 OFF**
     I_{IN} = 590.7mA ~ 608.7mA
     V_{OUT} = 3.267 ~ 3.367V
     V_{RIPPLE} ≤ 35mV
   - For V_{OUT} = 5V; **JP2 ON**
     I_{IN} = 931.07mA ~ 957.4mA
     V_{OUT} = 4.859 ~ 5.0075V
     V_{RIPPLE} ≤ 40mV
6. Check the switching waveform at scope CH1 to see whether it is a normal continuous conduction mode switching node waveform and switching ON time (T_{ON}) is between 0.46 µs ~ 1.15 µs